

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

AKRAM ALI SALMAN  
XUEJUN ZHAO  
KURT O. TAYLOR  
STEPHEN G. BEEBE

Examiner: Laura M. Schillinger

Group Art Unit: 2813

Att'y Docket: 2000.111200/H2022

Customer No.: 23720

Serial No.: 10/664,665

Filed: September 18, 2003

For: METHOD FOR DETERMINING THE  
RELIABILITY OF DIELECTRIC  
LAYERS

**RESPONSE TO OFFICE ACTION DATED DECEMBER 29, 2005**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

This paper is submitted in response to the Office Action dated December 29, 2005, for which the three-month date for response is March 29, 2006.

No fees are believed to be due in connection with the present paper. **However, should any fees be required under 37 C.F.R. §§ 1.16 to 1.21, the Director is authorized to deduct such fees from the Advanced Micro Devices, Inc. Deposit Account No. 01-0365/H2022.<sup>1</sup>**

Reconsideration of the application in view of the following amendments and remarks is respectfully requested.

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<sup>1</sup> In the event the monies in that account are insufficient, the Director is authorized to withdraw funds from Williams, Morgan & Amerson, P.C. Deposit Account No. 50-0786/2000.111200.